


Search Notes 	Application/Control No. 10829295	Applicant(s)/Patent Under Reexamination INOUE ET AL.
	Examiner Jonathan R Beckley	Art Unit 4178

SEARCHED

Class	Subclass	Date	Examiner
379	100.07,100.04	11/20/2007	JB
358	468,407,402,404,518,1.18,1.15,402,1.15,403,1.14,1.13,1.12	11/20/2007	JB
705	2,58,51,75,73,26,,71,43,64	11/20/2007	JB
348	231.9, 552,239,231.3,	11/20/2007	JB
380	54	11/20/2007	JB
709	206,223	11/20/2007	JB
715	839	11/20/2007	JB
718	102	11/20/2007	JB
382	233,100	11/20/2007	JB
400	61	11/20/2007	JB
700	241	11/20/2007	JB
434	350	11/20/2007	JB
358	468,407,402,404,518,1.18,1.15,402,1.15,403,1.14,1.13,1.12	6/9/2008	JB
379	100.07,100.04	6/9/2008	JB
705	2,58,51,75,73,26,,71,43,64	6/9/2008	JB
348	231.9, 552,239,231.3,	6/9/2008	JB
358	468,407,402,404,518,1.18,1.15,402,1.15,403,1.14,1.13,1.12	5/18/2009	JB
709	206,223	5/18/2009	JB

SEARCH NOTES

Search Notes	Date	Examiner
EAST	11/19/2007	JB
EAST	11/20/2007	JB
CONSULTED WITH HAI TRAN	11/19/2007	JB
EAST	6/9/2008	JB
EAST	5/18/2009	JB
EAST	5/16/2009	JB
CONSULTED WITH TWYLER HASKINS	5/19/2009	JB
CONSULTED WITH GARBIEL GARCIA	5/18/2009	JB
CONSULTED WITH EIC (STIC)	5/18/2009	JB

/JONATHAN R BECKLEY/
Examiner,Art Unit 2625

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

/JONATHAN R BECKLEY/ Examiner,Art Unit 2625	
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